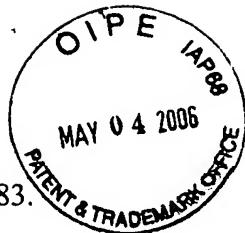


03500.017983.



IFW

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
TADAHIKO HIRAI, et al.) Examiner: Not Yet Assigned
Application No.: 10/538,036) Group Art Unit: Not Yet Assigned
Filed: June 8, 2005)
For: DRIVING METHOD OF)
INTEGRATED CIRCUIT) May 3, 2006

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed below and on the enclosed Form PTO-1449.

- (1) U.S. Patent Publication No. 2002/0195968
- (2) U.S. Patent Publication No. 2003/0016190
- (3) U.S. Patent Publication No. 2003/0052614
- (4) JP 7-013518
- (5) JP 5-094150
- (6) EP 1 132 882
- (7) EP 1 191 512
- (8) J. H. Wei, et al., "Improved stability of deuterated amorphous silicon thin film transistors", *Journal Of Applied Physics*, vol. 85, No. 1, pp, 543-550, (January 1, 1999).

(9) H. Hamada, "Sharp Technical Report", No. 69 (1997), p. 75.

Copies of documents (4), (5), (6), (7) and (8) are enclosed. Applicant is currently attempting to obtain a copy of document (9) and will provide a copy to the office in due course.

Documents (1), (2), (3), (6) and (7) were cited in an International Search Report, and document (3) was also cited in a Written Opinion, both issued in International Application No. PCT/JP2004/004189 from which the subject application claims priority. Copies of the International Search Report and Written Opinion were submitted with the subject application on June 8, 2005. In addition, a copy of each of these documents is being submitted herewith. English-language abstracts for each of the above-listed Japanese documents (4) and (5) have been located and are enclosed, and are believed to provide a concise explanation of relevance for each document.

Documents (8) and (9) are discussed in the specification at page 2, document (5) is discussed in the specification at page 10 and document (4) is discussed in the specification at page 11.

The Examiner's attention is also directed to the following U.S. Application:

| <u>APPLICATION NO.</u> | <u>FILING DATE</u> | <u>GROUP ART UNIT</u> |
|------------------------|--------------------|-----------------------|
| 10/538,037 | June 8, 2005 | 2876 |

The specification, drawings and claims for U.S. Application No. 10/538,037 are available in the Patent Office's Image File Wrapper; therefore, a copy of the application is not provided herein.

Inasmuch as the subject application has not yet received a first Office Action, it is believed that this Information Disclosure Statement is timely. See 37 C.F.R. § 1.97 (b)(3). Accordingly, the Examiner is urged to study this information in its entirety and

to form an independent determination of the materiality of the information to the claimed invention. Additionally, the Examiner is requested to indicate that this information has been considered by initialing the appropriate portion of Form PTO-1449 and to return the initialed form to Applicants with the next communication.

Applicants' undersigned attorney may be reached in our Costa Mesa, California office by telephone at (714) 540-8700. All correspondence should continue to be directed to our address given below.

Respectfully submitted,



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03500.017983.APPLICATION NO.
10/538,036APPLICANT
TADAHIKO HIRAI, et al.

MAY 04 2006

FILING DATE
June 8, 2005GROUP
NYAPATENTS & TRADEMARK OFFICE
U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|--|--|------------|-----------------|-------|----------|---------------------------------|
| | 2002/0195968 | 12/26/2002 | Sanford, et al. | 315 | 169.3 | |
| | 2003/0016190 | 01/23/2003 | Kondo | 345 | 55 | |
| | 2003/0052614 | 03/20/2003 | Howard | 315 | 169.1 | |
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| FOREIGN PATENT DOCUMENTS | | | | | | |
| | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES/NO/ OR ABSTRACT |
| | 1 132 882 | 03/06/2001 | EUROPE | | | |
| | 1 191 512 | 09/20/2001 | EUROPE | | | |
| | 7-013518 | 01/17/1995 | JAPAN | | | Abstract |
| | 5-094150 | 04/16/1993 | JAPAN | | | Abstract |
| | | | | | | |
| OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | |
| | J. H. Wei, et al., "Improved stability of deuterated amorphous silicon thin film transistors", <i>Journal Of Applied Physics</i>, vol. 85, No. 1, pp. 543-550, (January 1, 1999). | | | | | |
| | H. Hamada, "Sharp Technical Report", No. 69 (1997), p. 75. | | | | | |
| EXAMINER | | | DATE CONSIDERED | | | |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1